

Dual N-Channel Enhancement Mode Power MOSFET

DESCRIPTION

The HM4822 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

GENERAL FEATURES

V_{DS} =30V,I_D =10A

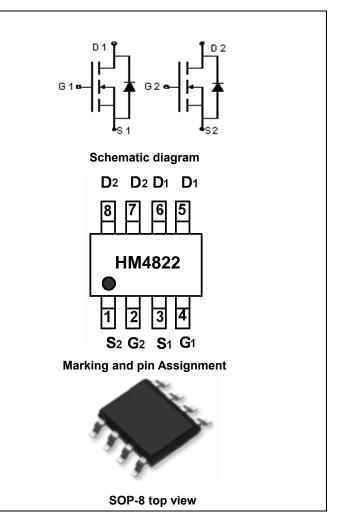
 $R_{DS(ON)} < 13.5 m\Omega$ @ $V_{GS} \text{=} 10 V$

 $R_{DS(ON)}$ < 20m Ω @ V_{GS} =4.5V

- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current

Application

- Power switching application
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply



Package Marking And Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity	
HM4822	HM4822	SOP-8	Ø330mm	12mm	2500 units	

Absolute Maximum Ratings (TA=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	30	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	I _D	10	А
Drain Current-Continuous(T _C =100°C)	I _D (100℃)	6	Α
Pulsed Drain Current	I _{DM}	50	Α
Maximum Power Dissipation	P _D	2.5	W
Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 150	$^{\circ}$ C

Thermal Characteristic

Thermal Resistance, Junction-to-Case(Note 2)	R _{eJC}	50	°C/W
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Electrical Characteristics (TA=25°C unless otherwise noted)

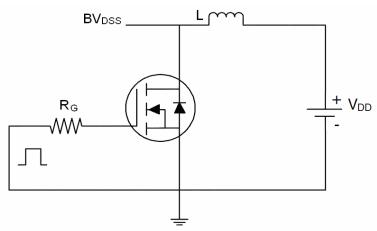
Parameter	Symbol	Condition	Min	Тур	Max	Unit	
Off Characteristics							
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	30	33	-	V	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =30V,V _{GS} =0V	V _{DS} =30V,V _{GS} =0V -		1	μA	
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA	
On Characteristics (Note 3)							
Gate Threshold Voltage	$V_{GS(th)}$	V_{DS} = V_{GS} , I_D =250 μ A	1	1.6	3	V	
	Б	V_{GS} =10V, I_D =10A	-	7.5	13.5	- mΩ	
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =4.5V, I _D =5A	-	11	20		
Forward Transconductance	g FS	V _{DS} =5V,I _D =10A	15	-	-	S	
Dynamic Characteristics (Note4)			•				
Input Capacitance	C _{lss}	\/ -45\/\/ -0\/	-	1550	-	PF	
Output Capacitance	Coss	V_{DS} =15V, V_{GS} =0V, F=1.0MHz	-	300	-	PF	
Reverse Transfer Capacitance	C _{rss}	r-1.0Winz	-	180	-	PF	
Switching Characteristics (Note 4)							
Turn-on Delay Time	t _{d(on)}		-	30	-	nS	
Turn-on Rise Time	t _r	V_{DD} =25 V , I_{D} =1 A	-	20	-	nS	
Turn-Off Delay Time	t _{d(off)}	V_{GS} =10 V , R_{GEN} =6 Ω	-	100	-	nS	
Turn-Off Fall Time	t _f		-	80	-	nS	
Total Gate Charge	Qg	\/ -15\/ L -10\	-	13	-	nC	
Gate-Source Charge	Q _{gs}	V_{DS} =15V, I_{D} =10A, V_{GS} =5V	-	5.5	-	nC	
Gate-Drain Charge	Q_{gd}	v _{GS} -5v	-	3.5	-	nC	
Drain-Source Diode Characteristics							
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =10A	-	-	1.2	V	
Diode Forward Current (Note 2)	Is		-	-	10	Α	

Notes:

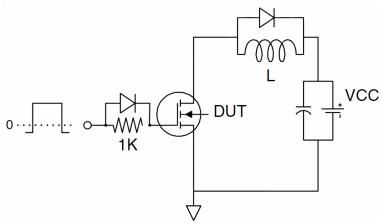
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.
- **4.** Guaranteed by design, not subject to production

Test circuit

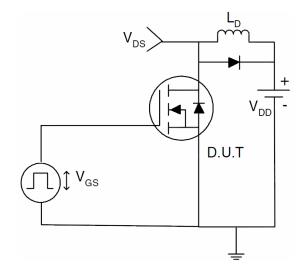
1) E_{AS} test Circuits



2) Gate charge test Circuit:



3) Switch Time Test Circuit:



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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (Curves)

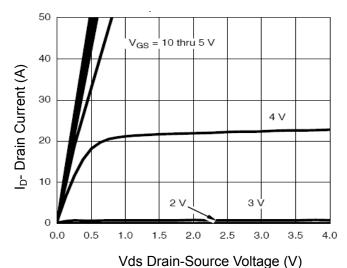
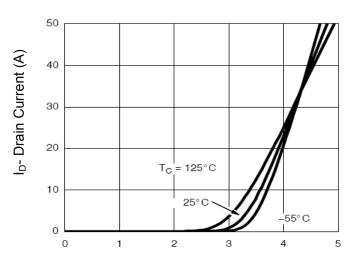


Figure 1 Output Characteristics



Vgs Gate-Source Voltage (V)
Figure 2 Transfer Characteristics

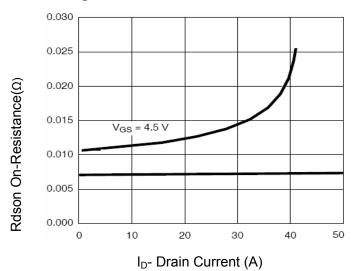


Figure 3 Rdson- Drain Current

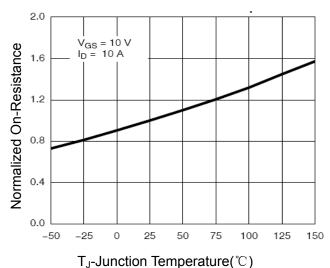


Figure 4 Rdson-JunctionTemperature

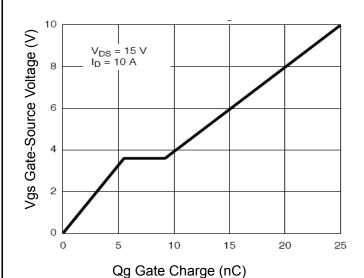


Figure 5 Gate Charge

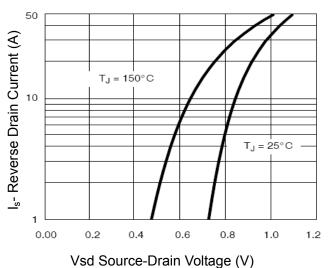


Figure 6 Source- Drain Diode Forward

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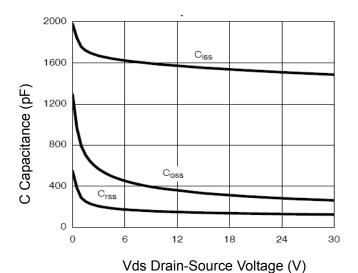
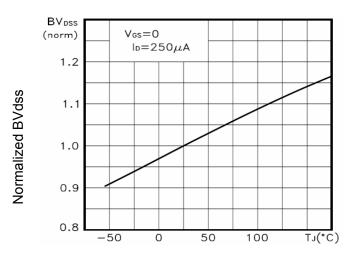
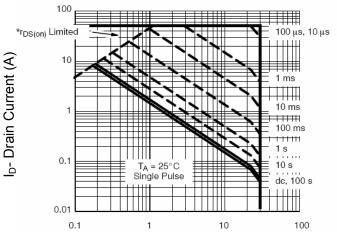


Figure 7 Capacitance vs Vds



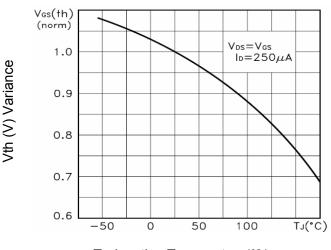
T_J-Junction Temperature(°C)

Figure 9 BV_{DSS} vs Junction Temperature



Vds Drain-Source Voltage (V)

Figure 8 Safe Operation Area



T_J-Junction Temperature(°C)

Figure 10 V_{GS(th)} vs Junction Temperature

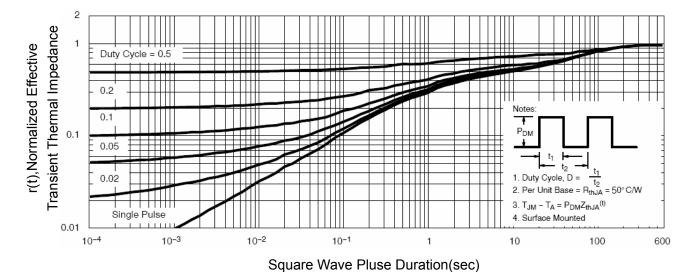
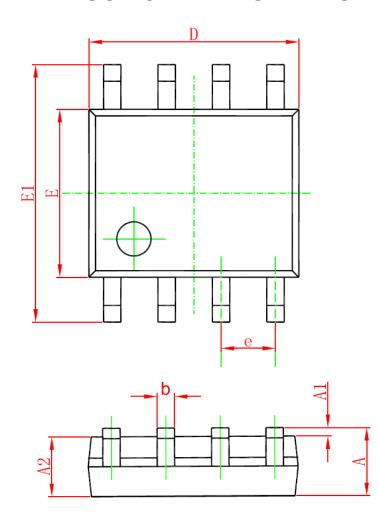


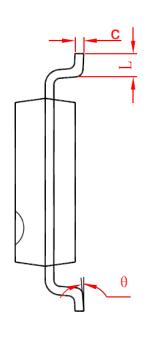
Figure 11 Normalized Maximum Transient Thermal Impedance

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SOP-8 PACKAGE IN FORMATION





C. mb a l	Dimensions In	n Millimeters	Dimensions In Inches		
Symbol	Min	Max	Min	Max	
A	1. 350	1. 750	0. 053	0. 069	
A1	0. 100	0. 250	0.004	0. 010	
A2	1. 350	1. 550	0. 053	0. 061	
b	0. 330	0. 510	0. 013	0. 020	
С	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
Е	3. 800	4. 000	0. 150	0. 157	
E1	5. 800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
L	0. 400	1. 270	0. 016	0. 050	
θ	0°	8°	0°	8°	

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